

simultaneously [imaging patterns] producing images of patterns at two points in proximity to the center of said workpiece with two imaging means provided at said pair of cutting blade units, and aligning said workpiece such that the [imaged current image] images of the patterns at said two points can match with said reference patterns; and

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moving either one of said two imaging means to a position so as to produce an image of a pattern at one point at the outer circumference of said workpiece and aligning said workpiece such that the [imaged current] image of the pattern at the point at the outer circumference can match with said reference patterns.

*b6*  
*bx*  
*32* (Amended) A method of aligning cutting lines of a workpiece, which depend on patterns, [such as ICs,] with a pair of cutting blades provided at a pair of cutting blade units provided with motors for rotating said pair of cutting blades, the alignment being performed when said pair of cutting blade units cuts said workpiece, said alignment method comprising the steps of:

[previously] registering reference patterns at at least one point of low magnification and one point of high magnification on said workpiece located at a preset position;

simultaneously [imaging patterns] producing images of patterns at two points in proximity to the center of said workpiece with two imaging means provided at said pair of cutting blade units, and aligning said workpiece such that the [imaged current image] images of the patterns at said two points can match with said reference patterns of the low magnification;

moving at least one of said two imaging means to a position so as to produce an image of a pattern at one point at the outer circumference of said workpiece [to image the pattern] and aligning said workpiece such that the [imaged current] image of the pattern at the [imaged] point at the outer circumference can match with said at least one reference pattern[s] of the low magnification;

switching the magnification from the low magnification to the high magnification, [imaging] producing a second image of a pattern at one point at the outer circumference of said workpiece with said at least one of said two imaging means, and aligning said workpiece so that the [imaged current pattern] second image at the point at the outer circumference can match with said at least one reference pattern[s] of high magnification; and

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